

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10660710	NAKANO ET AL.
	<b>Examiner</b> LUONG T NGUYEN	<b>Art Unit</b> 2622

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
348/294, 312, 317, 322, 262, 263 (text search)	11/07/09	LTN
EAST (USPAT; USPGPUB; JPO; EPO; DERWENT; IBM_TDB) see search history	11/07/09	LTN
348/272 (text search)	07/01/10	LTN
EAST (USPAT; USPGPUB; JPO; EPO; DERWENT; IBM_TDB) see search history	07/01/10	LTN
updated East	02/27/11	LTN
348/294, 312, 322, 302 (text search)	06/20/11	LTN
EAST (USPAT; USPGPUB; JPO; EPO; DERWENT; IBM_TDB) see search history	06/20/11	LTN
Inventorship search	06/20/11	LTN

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
	USPAT; USPGPUB; UPAD text search, see interference search history	06/20/11	LTN

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